(Do Not Enter again Same on EDAN

Search Notes



Application/Control No.

Applicant(s)/Patent under Reexamination

SEBIRE ET AL.

Art Unit

Binh Q. Nguyen

09/937,949

Examiner

2664

SEARCHED					
Class	Subclass	Date	Examiner		
370	329,336, 347-349	8/29/2005	BQN		
370	468	8/29/2005	BQN		
370	470	8/29/2005	BQN		
370	435	8/30/2005	BQN		
370	442	8/30/2005	BQN		
455	466	8/29/2005	BQN		
455	458	8/29/2005	BQN		
375	296	8/31/2005	BQN		
375	141	8/31/2005	BQN		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	<u> </u>				

SEARCH NOT (INCLUDING SEARCH)
	DATE	EXMR
EAST (US-PGPUB; USPAT; USOCR; EPO; JPO; DERWENT; IBM-TDB) see search history	8/29/2005	BQN
Consulted with Wellington Chin	8/29/2005	BQN